

“Point defect clusters and dislocations in FIB irradiated nanocrystalline aluminum films : an electron tomography and aberration-corrected high-resolution ADF-STEM study”. Idrissi H, Turner S, Mitsuhashi M, Wang B, Hata S, Coulombier M, Raskin J-P, Pardoën T, Van Tendeloo G, Schryvers D, *Microscopy and microanalysis* **17**, 983 (2011).
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